# **ANTENNA**

ISSUED BY Shenzhen BALUN Technology Co., Ltd.



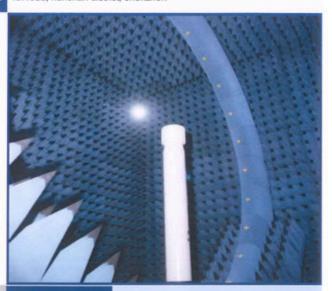
FOR

#### mouse module

**ISSUED TO** SHENZH BOYCHUANG TECHNOLOGY CO., LTD

TESTREPORT

Room 407-408, skyworth semiconductor building, no.18, gaoxin south 4th road, nanshan district, shenzhen





Report No: BL-SZ1998167-901 **EUT Name:** mouse module Model Name: HS6210 Brand Name: Test Standard: IEEE149-1979 Maximum: Gain: -4.62 (dBi) Efficiency: 11%

Test Date: Sep. 20, 2019 Date of Issue: Sep. 27, 2019

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# **Revision History**

 Version
 Issue Date
 Revisions

 Rev. 01
 Sep. 27, 2019
 Initial Issue

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# 1 Administrative Data (GENERAL INFORMATION)

# 1.1 Identification of the Testing Laboratory

Company Name Shenzhen BALUN Technology Co., Ltd.	
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6685 0100

#### 1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.	
Address	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China	
Accreditation Certificate	The laboratory is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L6791. The laboratory is a testing organization accredited by China Metrology Accreditation (CMA). The accreditation certificate number is 2017192290Z.	
Description  All measurement facilities used to collect the measurement data located at Block B, FL 1, Baisha Science and Technology Park, Sl Xi Road, Nanshan District, Shenzhen, Guangdong Province, & China 518055		

# 1.3 Laboratory Condition

Ambient Temperature	19°C to 25°C
Ambient Relative Humidity	45% to 55%
Ambient Pressure	100 kPa to 102 kPa

#### 1.4 Announce

- (1) The test report reference to the report template version v2.2.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (5) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (6) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.



# **2 PRODUCT INFORMATION**

# 2.1 Applicant Information

Applicant	SHENZH BOYCHUANG TECHNOLOGY CO., LTD	
Address Room 407-408, skyworth semiconductor building, no.18, gao 4th road, nanshan district, shenzhen		
Contact Person	QIAN.YI	
Telephone Number	13612864217	
E-mail Address	qian.yi@huntersun.com.cn	

#### 2.2 Manufacturer Information

Manufacturer SHENZH BOYCHUANG TECHNOLOGY CO., LTD	
Addesses	Room 407-408, skyworth semiconductor building, no.18, gaoxin south
Address	4th road, nanshan district, shenzhen

# 2.3 Factory Information

Factory	N/A
Address	N/A

# 2.4 General Description for Equipment under Test (EUT)

EUT Name	mouse module
Model Name Under Test	HS6210
Antenna Type	PCB Antenna
Dimensions	12mm * 6mm

# 2.5 Ancillary Equipment

Note: Not applicable.

#### 2.6 Technical Information

Frequency Range	2402MHz ~ 2480MHz	
Test Frequencies	2402MHz, 2441MHz, 2480MHz	



# 3 SUMMARY OF TEST RESULTS

# 3.1 Test Standards

No.	Identity	Document Title
1	IEEE149-1979	IEEE Standard Test Procedures for Antennas

# 3.2 Test Verdict

Report Section	Description	Remark
ANNEX A.1	Gain and Efficiency	-
ANNEX B	Radiation Pattern	

#### 3.3 Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Item	Uncertainty
VSWR(S11)	±0.2
Gain	±0.5dB



# **4 GENERAL TEST CONFIGURATIONS**

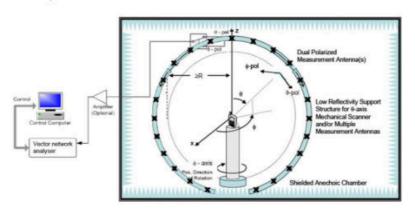
# 4.1 Test Condition

Manager Local	Selected Values During Tests					
Environment Parameter	Ambient Pressure(KPa)	remperature( c)	Voltage	Relative Humidity (%)		
Normal Temperature, Normal Voltage (NTNV)	100 to 102	19 to 25	N/A	45 to 55		

# 4.2 Test Equipment List

Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due
Vector Network Analyzer	Agilent	E5071C	MY46103472	2019.02.28	2020.02.27
SG24 Multi-probe Antenna Measurement System	SATIMO	SG24-L	1101855- 0001	2018.06.22	2020.06.21

# 4.3 Test Setup



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# ANNEX A TEST RESULTS

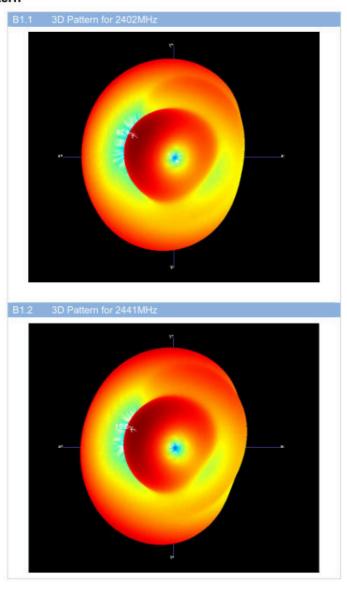
# A.1 Gain and Efficiency

Frequency	Gain (dBi)	Efficiency (%)	
2402MHz	-4.75	11	
2441MHz	-5.51	11	
2480MHz	-4.62	10	

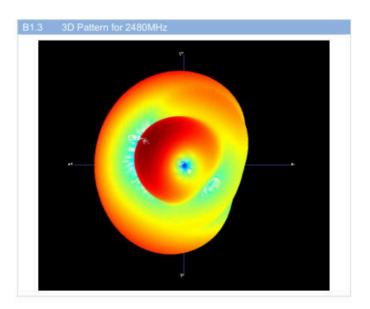


# ANNEX B RADIATION PATTERN

# B.1 3D Pattern

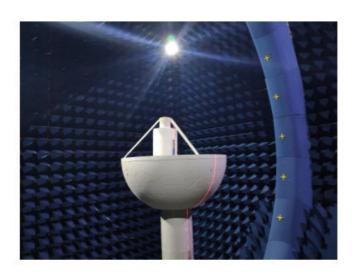








# ANNEX C TEST SETUP PHOTO





# ANNEX D EUT PHOTO

